

Search Notes**Application/Control No.**

10/757,974

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

TIHANYI, JENOE

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	380	02.07.05	Hiep
	383	—	—
	384	—	—
	427	—	—
327	374	07.25.05	Hiep
	375	—	—
	376	—	—
	377	—	—
	378	—	—

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	02.07.05	Hiep
EAST	07.25.05	Hiep

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner